

EV 182659599

Sheet 1 of 8

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765RECEIVED  
NOV 4 2002  
TC 1700

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
LJNE	AA 4,381,201	04/26/83	Sakurai	148	1.5	
LJNE	AB 4,472,729	09/18/84	Shibata et al.	357	49	
LJNE	AC 4,489,478	12/25/84	Sakurai	29	574	
LJNE	AD 4,681,657	07/21/87	Hwang et al.	156	657	
LJNE	AE 4,753,709	06/28/88	Welch et al.	156	643	
LJNE	AF 4,807,016	02/21/89	Douglas	357	67	
LJNE	AG 4,818,335	04/04/89	Karnett	156	644	
LJNE	AH 4,966,865	10/30/90	Welch et al.	437	192	
LJNE	AI 5,037,777	08/06/91	Mele et al.	437	195	
LJNE	AJ 5,063,169	11/05/91	DeBruin et al.	437	41	
LJNE	AK 5,084,417	01/28/92	Joshi et al.	437	192	

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation
					Yes No
LJNE AL 56-114355	09.08.81	Japan (Yoji)			Abstract
LJNE AM 60-42821	03.07.85	Japan (Mitsubishi Electric Corp)			Abstract
LJNE AN 61-133555	12.09.86	Japan (Varta Batterie)			X
LJNE AO 0 265 584 A2	05.05.87	EPO (IBM)			

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

LJNE	AP	Abatchev et al., Study of the Boron-Phosphorous Doped and Undoped Silicate Glass Etching in CHF <sub>3</sub> /Ar Plasma, 96 ELECTROCHEM SOC. PROCEEDINGS, No. 12, pp. 522-530 (1996).
LJNE	AO	Ikegami et al., Mechanisms of High PSG/SiO <sub>2</sub> Selective Etching in a Highly Polymerized Fluorocarbon Plasma, 30 JAP. J. APPL. PHYS., No. 7, pp. 1556-1561 (July 1991).

EXAMINER

Lynette J. Ung-Evmini

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
LJONE	AA 5,150,276	09/22/92	Gonzalez et al.	361	313	
LJONE	AB 5,192,703	03/09/93	Lee et al.	437	52	
LJONE	AC 5,208,176	05/04/93	Ahmad et al.	437	47	
LJONE	AD 5,210,047	05/11/93	Woo et al.	437	43	
LJONE	AE 5,252,517	10/12/93	Blalock et al.	437	195	
LJONE	AF 5,286,344	02/15/94	Blalock et al.	156	657	
LJONE	AG 5,298,465	03/29/94	Levy	437	225	
LJONE	AH 5,312,768	05/17/94	Gonzalez	437	40	
LJONE	AI 5,321,286	06/14/94	Koyama et al.	257	315	
LJONE	AJ 5,323,047	06/21/94	Nguyen	257	384	
LJONE	AK 5,362,666	11/08/94	Dennison	437	52	

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation
					Yes No
LJONE AL 0 465 044 A2	19.06.91	EPO (AT&T)			
LJONE AM 4-345054	12.01.92	Japan (Ricoh Co.)			X
LJONE AN 0 498 614 A1	23.01.92	EPO (NEC Corp.)			
AO 4-360570	14.12.92	Japan (Mitsubishi Electric Corp.)			Abstract

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

LJONE	AP	van den Hoek et al., <i>Isotropic plasma etching of doped and undoped silicon dioxide for contract holes and vias</i> , 7 J. VAC. SCI. TECHNOL., No. 3, pp. 670-675 (May/June 1989).
	AQ	

EXAMINER

Lynette T. Umz-Euruni

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
LJONE	AA 5,386,590	11/22/94	Kadomura	156	662	
LJONE	AB 5,374,332	12/20/94	Koyama et al.	156	643	
LJONE	AC 5,401,681	03/28/95	Dennison	437	60	
LJONE	AD 5,422,308	06/06/95	Nicholls et al.	437	192	
LJONE	AE 5,423,945	06/13/95	Marks et al.	156	662.1	
LJONE	AF 5,429,070	07/04/95	Campbell et al.	118	723	
LJONE	AG 5,445,712	08/29/95	Yanagida	156	662	
LJONE	AH 5,478,772	12/26/95	Fazan	437	60	
LJONE	AI 5,482,894	01/09/96	Havemann	437	195	
LJONE	AJ 5,485,035	01/16/96	Lin et al.	257	637	
LJONE	AK 5,550,071	08/27/96	Ryou	437	41	

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation
					Yes No
LJONE AL 5-335482	17.12.93	Japan (Semiconductor Energy)			Abstract
LJONE AM 0 680 084 A1	28.04.95	EPO (Texas Instruments, Inc.)			
LJONE AN 0 763 850 A1	30.08.96	EPO (Applied Materials, Inc.)			
LJONE AO WO 98/49719	05.11.98	WIPO (Micron Technology, Inc.)			

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AP		
AQ		

EXAMINER

Lynette T. Wong-Euruni

DATE CONSIDERED

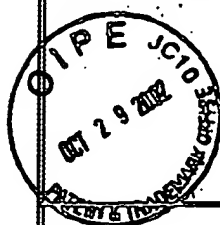
2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765

RECEIVED  
NOV 4 2002  
TC 1700

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.T.M.E.	AA	5,611,888	03/18/97	Bosch et al.	156	643.1	
L.T.M.E.	AB	5,626,716	05/06/97	Bosch et al.	438	723	
L.T.M.E.	AC	5,643,819	07/01/97	Tseng	437	60	
L.T.M.E.	AD	5,677,227	10/14/97	Yang et al.	437	60	
L.T.M.E.	AE	5,685,914	11/11/97	Hills et al.	118	723	
L.T.M.E.	AF	5,685,951	11/11/97	Torek et al.	156	646.1	
L.T.M.E.	AG	5,700,731	12/23/97	Lin et al.	438	381	
L.T.M.E.	AH	5,712,202	01/27/98	Liaw et al.	438	253	
L.T.M.E.	AI	5,731,130	03/24/98	Tseng	430	316	
L.T.M.E.	AJ	5,731,242	03/24/98	Parat et al.	438	586	
L.T.M.E.	AK	5,736,455	04/07/98	Iyer et al.	138	592	

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP		
	AO		

EXAMINER

Dyanette J. Wang-Evans

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
X.J.M.E	AA 5,747,369	05/05/98	Kantimahanti et al.	438	241	
X.J.M.E	AB 5,780,338	07/14/98	Jeng et al.	438	253	
X.J.M.E	AC 5,783,496	07/21/98	Flanner et al.	438	743	
X.J.M.E	AD 5,792,689	08/11/98	Yang et al.	438	253	
X.J.M.E	AE 5,792,703	08/11/98	Bronner et al.	438	620	
X.J.M.E	AF 5,817,579	10/06/98	Ko et al.	438	740	
X.J.M.E	AG 5,821,594	10/13/98	Kasai	257	410	
X.J.M.E	AH 5,851,896	12/22/98	Summerfelt	438	396	
X.J.M.E	AI 5,871,659	02/16/99	Sakano et al.	216	79	
X.J.M.E	AJ 5,883,436	03/16/99	Sadjadi et al.	257	760	
X.J.M.E	AK 5,897,352	04/27/99	Lin et al.	438	255	

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
					Yes	No
AL						
AM						
AN						
AO						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AP		
AQ		

EXAMINER

Lynette T. Wang-Evans

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
L.T.N.E.	AA	5,918,120	06/29/99	Huang	438	239	
L.T.N.E.	AB	5,936,272	08/10/99	Lee	257	306	
L.T.N.E.	AC	5,946,568	08/31/99	Hsiao et al.	438	253	
L.T.N.E.	AD	5,986,299	11/16/99	Nakamura et al.	257	296	
L.T.N.E.	AE	5,990,507	11/23/99	Mochizuki et al.	257	295	
L.T.N.E.	AF	6,074,488	06/13/00	Roderick et al.	118	728	
L.T.N.E.	AG	6,074,958	06/13/00	Tokunaga et al.	438	724	
L.T.N.E.	AH	6,117,788	09/12/00	Ko	438	706	
L.T.N.E.	AI	6,117,791	09/12/00	Ko et al.	438	723	
L.T.N.E.	AJ	6,121,671	09/19/00	Ko et al.	257	644	
L.T.N.E.	AK	6,124,199	09/26/00	Bohr	438	595	

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP		
	AQ		

EXAMINER

Lynette T. Hng-Euruni

DATE CONSIDERED

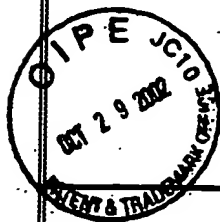
2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765
 RECEIVED  
 NOV 4 2002  
 TC 1700

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.T.H.E	AA	6,153,490	11/28/00	Xing et al.	438	396	
L.T.H.E	AB	6,159,862	12/12/00	Yamada et al.	438	712	
L.T.H.E	AC	6,165,880	12/26/00	Yaung et al.	438	592	
L.T.H.E	AD	6,171,970 B1	01/09/01	Xing et al.	438	706	
L.T.H.E	AE	6,174,451 B1	01/16/01	Hung et al.	216	67	
L.T.H.E	AF	6,183,655 B1	02/06/01	Wang et al.	216	68	
L.T.H.E	AG	6,242,759 B1	06/05/01	Yamazaki et al.	257	69	
L.T.H.E	AH	6,271,542 B1	08/07/01	Emma et al.	257	67	
L.T.H.E	AI	6,277,758 B1	08/21/01	Ko	438	706	
L.T.H.E	AJ	6,337,285 B1	01/08/02	Ko	438	714	
L.T.H.E	AK	6,432,833 B1	08/13/02	Ko	438	714	

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP		
	AQ		

EXAMINER

Lynette T. Umeg-Eumini

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-2037SERIAL NO.  
09/945,508LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

APPLICANT: Kei-Yu Ko

FILING DATE  
August 30, 2001GROUP  
1765
 RECEIVED  
 NOV 4 2002  
 TC 1760

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
L.JONE	AA	6,458,685 B2	10/01/02	Ko et al.	438	621	
L.JONE	AB	08/846,671		Ko (as filed and as amended)			04/30/1997
L.JONE	AC	09/532,088		Ko (as filed)			03/21/2000
L.JONE	AD	09/579,402		Ko (as filed and as amended)			05/25/2000
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AP		
	AO		

EXAMINER:

Lynette T. Ung-Eunim

DATE CONSIDERED

2/20/2003

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.